

<b>Notice of References Cited</b>		Application/Control No. 10/525,993	Applicant(s)/Patent Under Reexamination LEITNER ET AL.	
		Examiner Jason M. Berman	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,966,676	10-1990	Fukasawa et al.	204/298.12
*	B US-6,071,389	06-2000	Zhang, Hao	204/298.12
*	C US-5,077,990	01-1992	Plath, Ernst-Dieter	66/123
*	D US-2002/0084121	07-2002	Hulen, Michael S.	180/65.3
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 01096375 A	04-1989	Japan	ISHIKURA, CHIHIARU	
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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